

VM042D

• General Description

The VM042D is a 3 Stages analog High Power MMIC amplifier operating in the frequency range 8 to 12GHz. The device is a cascaded 3 stages amplifier designed in 0.25 μ m pHEMT process. The device is capable of 12W output power at Psat, and provides 25dB of large gain from 8 to 12GHz with less than 1dB of Gain variation.

The design has been optimized to provide high efficiency, supply current is 4.5A with $V_D = +8.5V$, when delivering 12W output power.

• Features

3 stages High Power pHEMT GaAs MMIC

Wide band **8 – 12GHz**

High Output P_{SAT} **12W**

High P1dB **> +40dBm**

High large signal gain **25dB typical**

50 Ω , AC coupled RF input and output

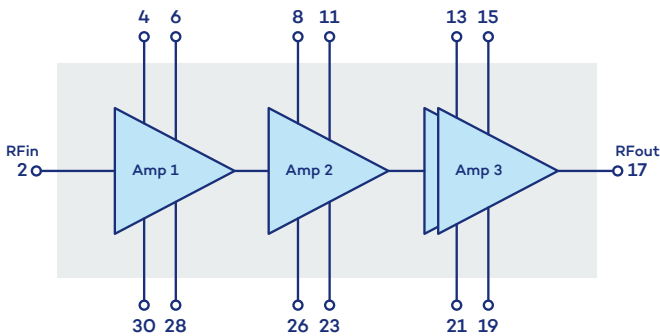
Power supply **4.5A @+8.5V; VG= -0.7V**

Chip size **4.5 x 3.9 x 0.1 (mm)**

• Applications

- X band High Power amplifier
- Broadband communication
- Radar
- Test and measurement

• Pins Assignment & Functional Block Diagram



Function	Pin number
RF in	2
V_{G1}	4 / 30
V_{G2}	8 / 26
V_{D1}	6 / 28
V_{D2}	11 / 23
V_{G3}	13 / 21
V_{D3}	15 / 19
RF out	17

• Electrical Specifications

Test conditions: unless otherwise noted

- $T_{amb} = +25^{\circ}\text{C}$
- $V_D = +28\text{V}$
- $V_G = -0.7\text{V}$
- Pulsed mode (pulse width: 10 μs , duty cycle: 10%)

Symbol	Parameter	Min	Typ	Max	Unit
F	Frequency range	8		12	GHz
G	Power gain		25		dB
ΔG	Gain flatness from 8 to 12GHz		+/-0.7		dB
S11	Input return loss		-10		dB
S22	Output return loss		-10		dB
P_{SAT}	Saturated output power		40.8		dBm
P1dB	Output power @1dB compression		40		dBm
I_{DQ}	Drain quiescent current		3.7		A
I_D Sat	Saturated drain current		4.0	4.6	A
PAE	Power added efficiency		35		%
	Small Signal Gain on 8-10GHz		27		dB
	Small Signal Gain on 10-12GHz		23		dB
	Pout Temperature Coef. $\{-40^{\circ}\text{C}/+70^{\circ}\text{C}, P_{in} = +18\text{dBm}\}$			0.01	dB/ $^{\circ}\text{C}$
	Small Signal Gain Temperature Coef. $\{-40^{\circ}\text{C}/+70^{\circ}\text{C}\}$		-0.032		dB/ $^{\circ}\text{C}$

• Environmental parameters

Symbol	Parameter	Min	Max	Unit
Tst	Storage temperature	-55	+85	$^{\circ}\text{C}$
Top	Operating temperature	-40	+85	$^{\circ}\text{C}$

• Absolute Maximum Ratings

Symbol	Parameter	Min	Max	Unit
V_D	Drain voltage		9	V
V_G	Gate voltage		-0.7	V
P_{in}	RF input power		+23	dBm
I_D	Drain bias current ($I_D = I_{D1} + I_{D2}$)		4	A
	Soldering temperature (10 seconds max.)		290	$^{\circ}\text{C}$
Tj	Junction temperature		+150	$^{\circ}\text{C}$

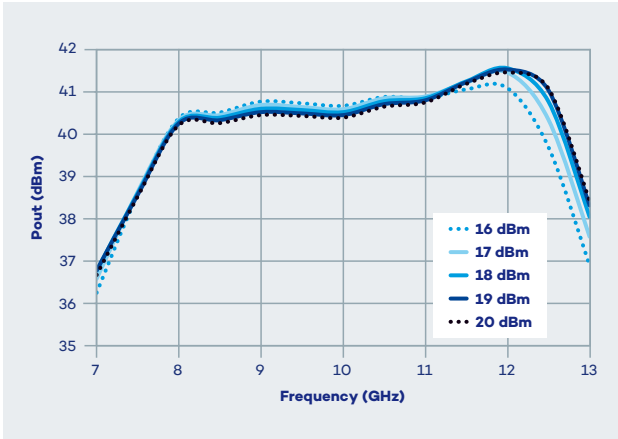
Care should be taken to avoid supply transient and over voltage. Over voltage above the maximum specified in absolute maximum rating section may cause permanent damage to the device.

• **Typical Performance**
(Test Under Probes)

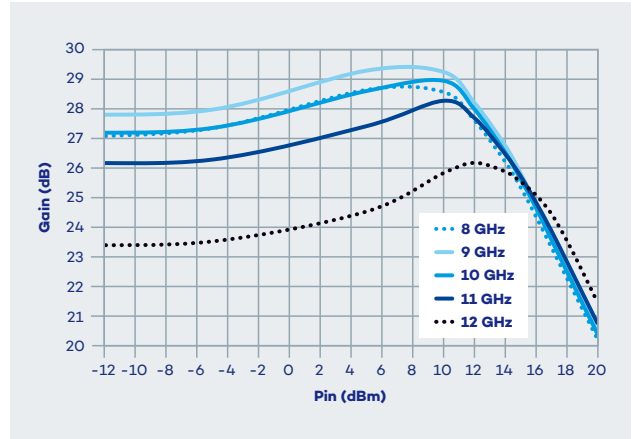
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- $I_D = 4.5A$ max
- Pulsed mode (pulse width: 10 μ s, duty cycle: 10%)

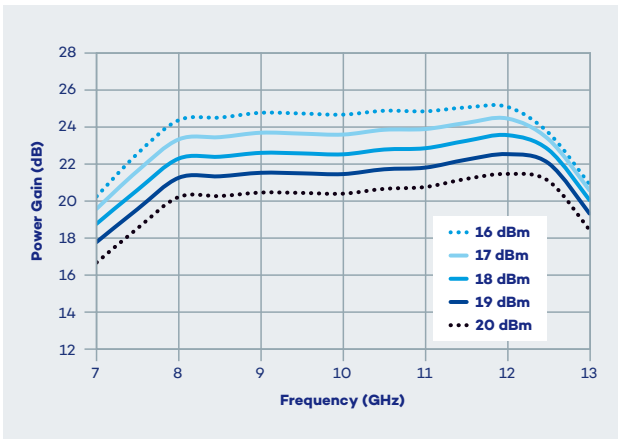
Output Power vs Frequency



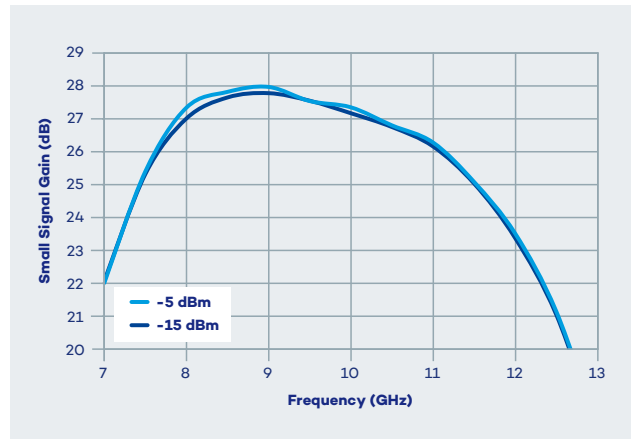
Gain vs Input Power vs Frequency



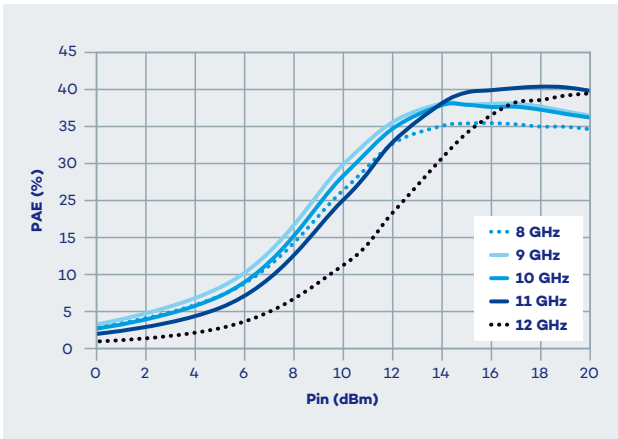
Power Gain vs Frequency vs Input Power



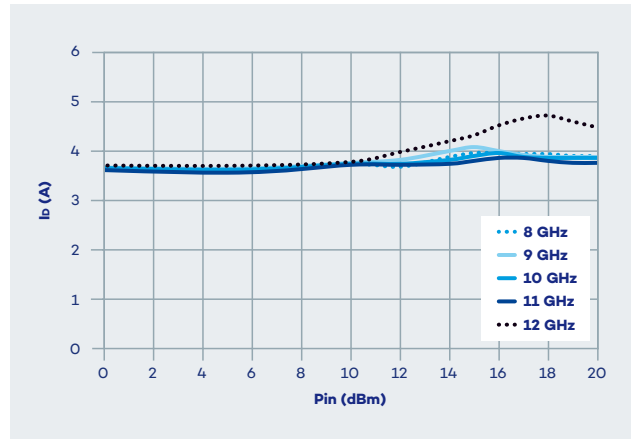
Small Signal Gain vs Frequency



PAE vs Input Power vs Frequency



I_D vs Input Power vs Frequency

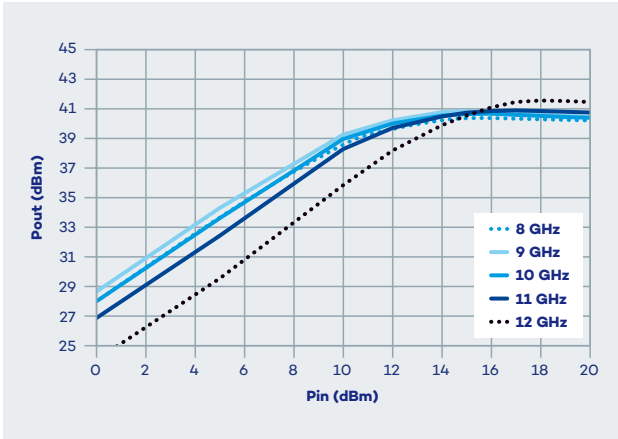


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(Test Under Probes)

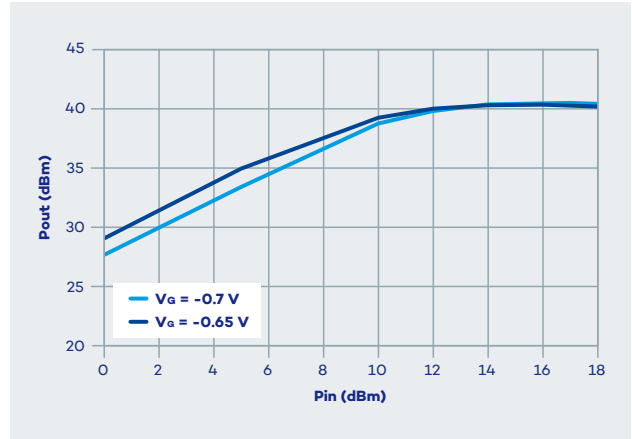
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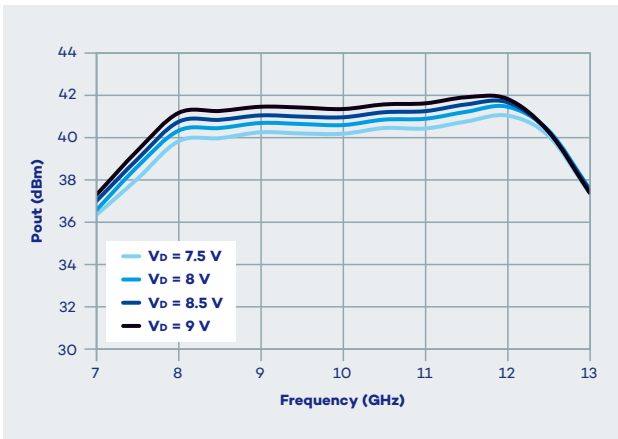
Output Power vs Input Power vs Frequency



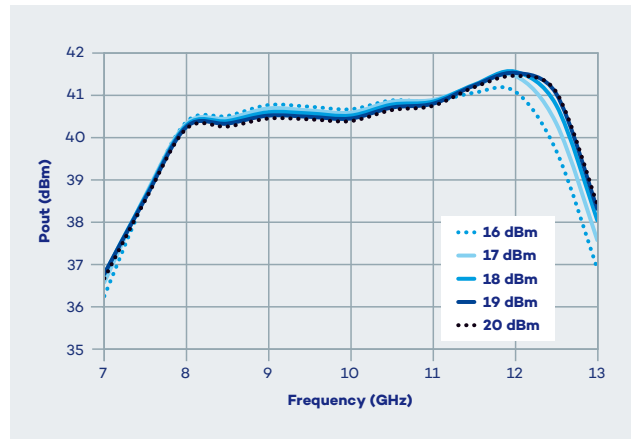
Output Power vs Input Power vs V_G



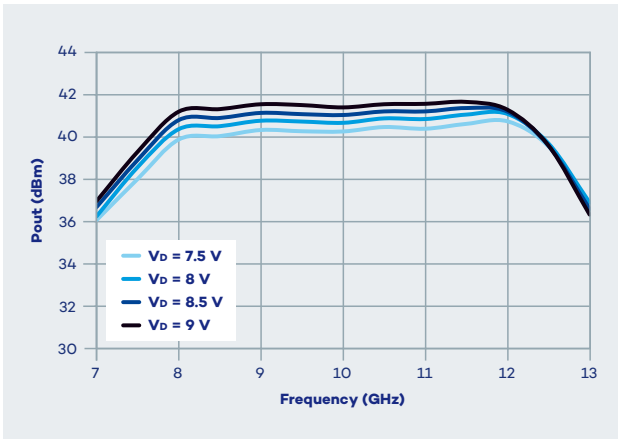
Output Power vs Frequency @17dBm vs V_D



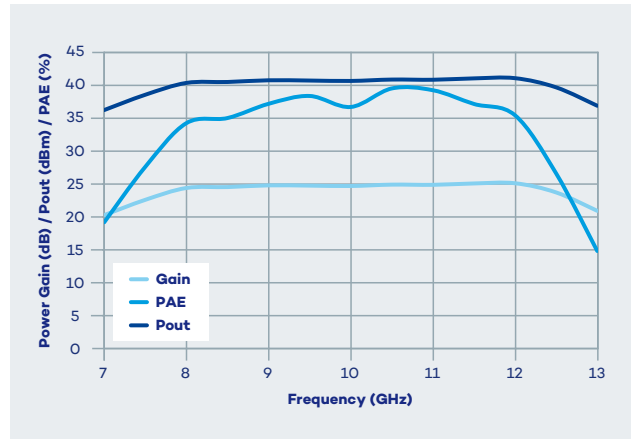
Output Power vs Frequency vs Input Power



Output Power vs Frequency @16dBm vs V_D



Output Power / Power Gain / PAE vs Frequency

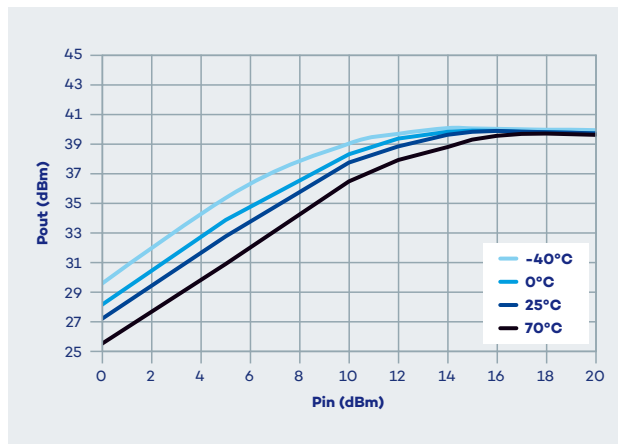


• **Typical Performance**
(Board Measurements)

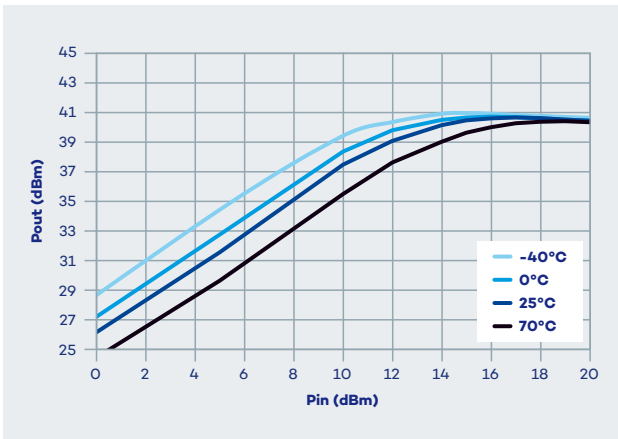
Test conditions: unless otherwise noted

- $T_{amb} = +25^{\circ}\text{C}$ - using heating cooler
- $V_D = +28\text{V}$
- $V_G = -0.7\text{V}$
- $I_D = 4.5\text{A max}$
- Pulsed mode (pulse width: $10\mu\text{s}$, duty cycle: 10%)

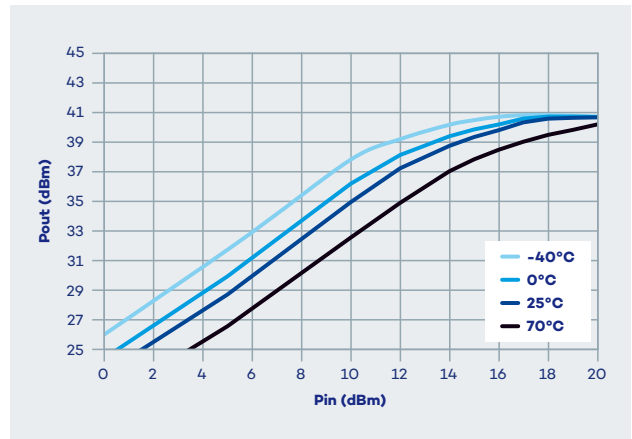
Output Power vs Input Power vs Temperature @ 8GHz



Output Power vs Input Power vs Temperature @ 10GHz



Output Power vs Input Power vs Temperature @ 12GHz

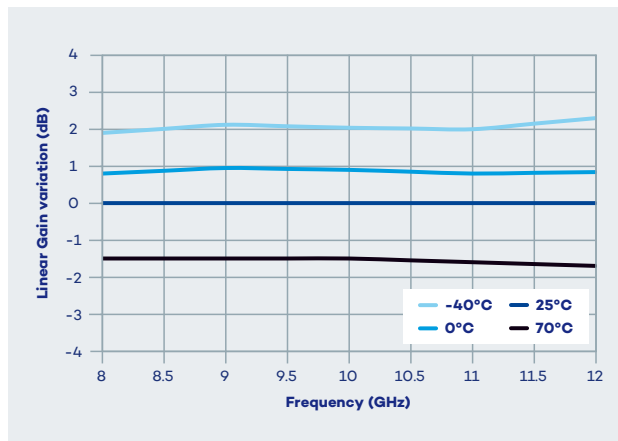


• **Typical Performance**
(Board Measurements)

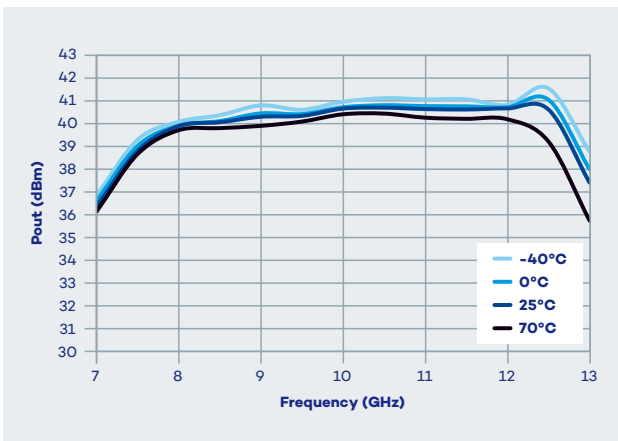
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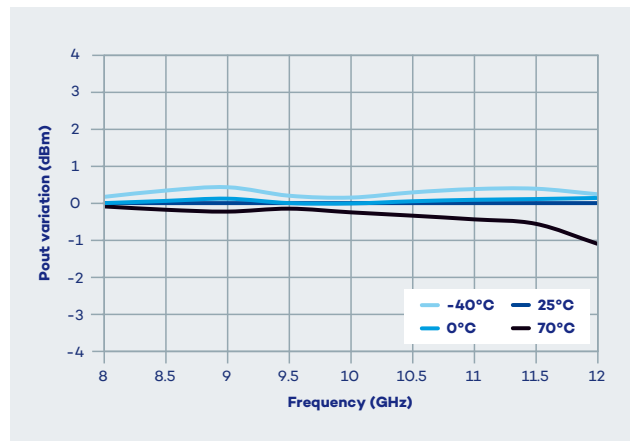
Linear Gain Variation vs Frequency vs Temperature



Input Power vs Frequency vs Temperature

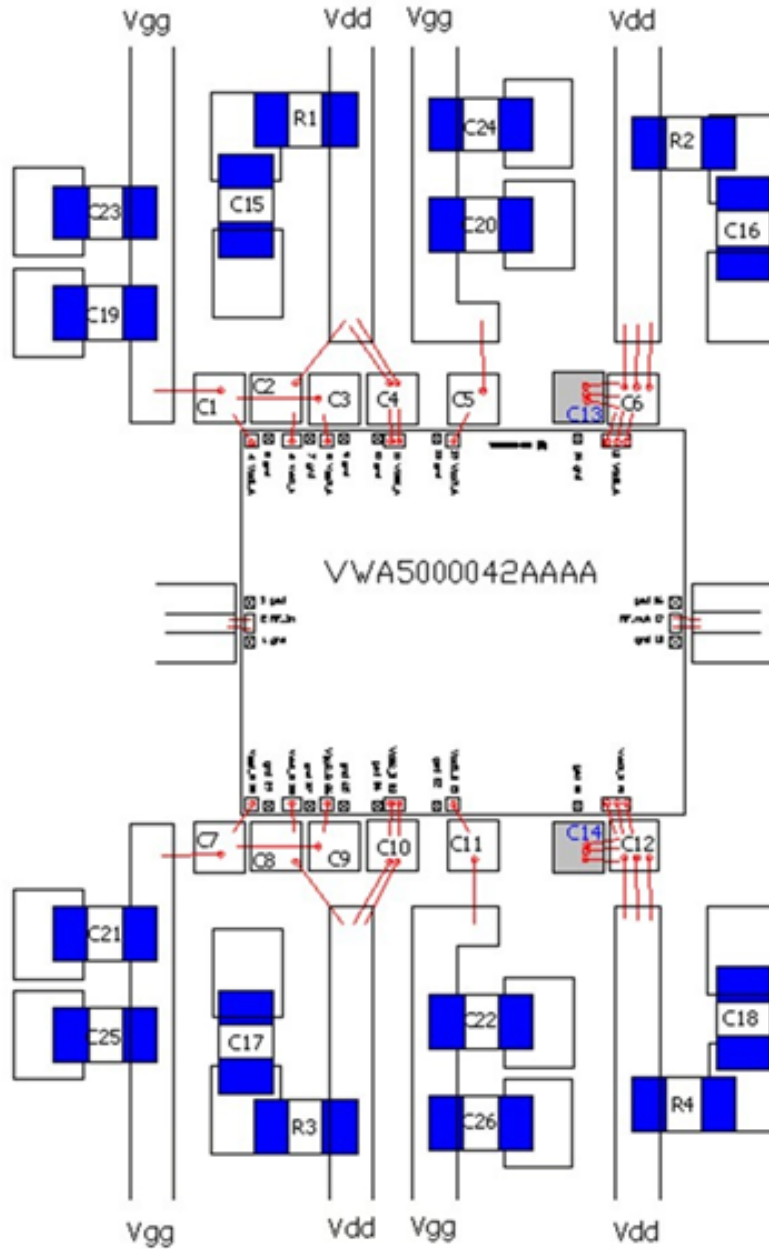


Input Power Variation vs Frequency vs Temperature



• **Application circuit**

- C1 to C12 = 100 pF MIM capacitor close to the die
- C13 and C14 = 10 nF MIM capacitor close to the die
- C15 and C18 = 220 nF
- C19 and C22 = 10nF
- C23 and 26 = 1 μ F
- R1 to R4 = 11 Ω



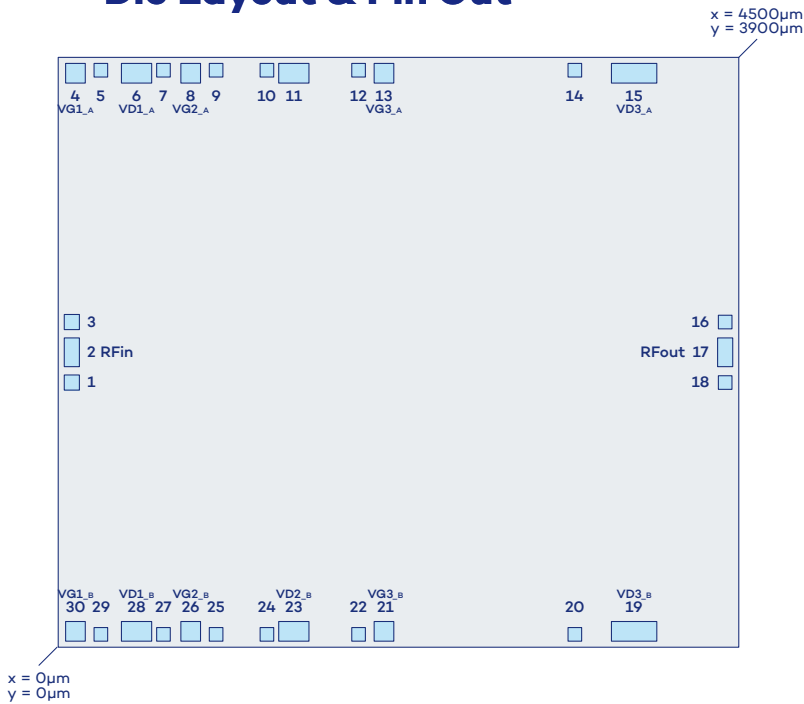
• **Bias-up procedure**

1. Apply $V_G = -3V$
2. Apply $V_D = +28V$
3. Adjust $V_G = -0.7V$
4. Apply RF signal in pulsed mode

• **Bias-down procedure**

1. Turn off RF signal
2. Reduce V_G to $-3V$
3. Apply $V_D = 0V$
4. Turn off power supply

• Die Layout & Pin Out



- Die size = 4500µm x 3900µm
- Die thickness = 100µm
- Die size tolerance = 50µm

Pad number	X (µm)	Pad center Y (µm)	Size (µm x µm)	Name	Function
1	90	1750	100 x 100	Gnd	
2	90	1950	100 x 190	RFin	RF Input
3	90	2150	100 x 100	Gnd	
4	114	3795	130 x 130	VG1_A	Gate Bias
5	282	3815	90 x 90	Gnd	
6	518	3795	200 x 130	VD1_A	Drain Bias
7	696	3815	90 x 90	Gnd	
8	876	3795	130 x 130	VG2_A	Gate Bias
9	1044	3815	90 x 90	Gnd	
10	1380	3815	90 x 90	Gnd	
11	1558	3795	200 x 130	VD2_A	Drain Bias
12	1986	3815	90 x 90	Gnd	
13	2154	3795	130 x 130	VG3_A	Gate Bias
14	3416	3815	90 x 90	Gnd	
15	3808	3795	300 x 130	VD3_A	Drain Bias
16	4410	2150	90 x 90	Gnd	
17	4410	1950	100 x 190	RFout	RF Output
18	4410	1750	90 x 90	Gnd	
19	3808	105	300 x 130	VD3_B	Drain Bias
20	3416	85	90 x 90	Gnd	
21	2154	105	130 x 130	VG3_B	Gate Bias
22	1986	85	90 x 90	Gnd	
23	1558	105	200 x 130	VD2_B	Drain Bias
24	1380	85	90 x 90	Gnd	
25	1044	85	90 x 90	Gnd	
26	876	105	130 x 130	VG2_B	Gate Bias
27	696	85	90 x 90	Gnd	
28	518	105	200 x 130	VD1_B	Drain Bias
29	282	85	90 x 90	Gnd	
30	114	105	130 x 130	VG1_B	Gate Bias

- Die bottom must be connected to ground (RF and DC)

• Ordering information

Product Code	Parameter
VM042D	8 to 12GHz - 25dB - 12W GaAs Power Amplifier

• Associated Material

- Packaged die
- Die Evaluation Board (die EVB)
- Packaged die Evaluation Board (packaged die EVB)
- Mechanical files (DXF)
- Measurements files (S2P)

• Product Compliance Information

Solderability

Use only AuSn (80/20) solder and limit exposure to temperature above 300 °C during 3-4 minutes, maximum.

ESD Sensitivity Rating

Test: Human Body Model (HBM)
Std: JEDEC Standard JESD22-A114



RoHS-Compliance

This part is compliant with EU 2011/65/EU RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment).

Other attributes

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C15H12Br4O2) Free
- PFOS Free
- SVHC Free

• Contact information

For the latest specifications, additional product information, worldwide sales and distribution locations, and information about Vectrawave.

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